

# checkCIF/PLATON report

Structure factors have been supplied for datablock(s) Coesite-IV\_44.18GPa

THIS REPORT IS FOR GUIDANCE ONLY. IF USED AS PART OF A REVIEW PROCEDURE FOR PUBLICATION, IT SHOULD NOT REPLACE THE EXPERTISE OF AN EXPERIENCED CRYSTALLOGRAPHIC REFEREE.

No syntax errors found.      CIF dictionary      Interpreting this report

## Datablock: Coesite-IV\_44.18GPa

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Bond precision:    Si- O = 0.0038 A                      Wavelength=0.28965

Cell:                      a=6.5586(4)                      b=6.9029(7)                      c=8.5429(8)  
                                    alpha=69.599(9)                      beta=83.035(6)                      gamma=81.933(6)  
Temperature:    296 K

	Calculated	Reported
Volume	357.83(6)	357.83(6)
Space group	P -1	P -1
Hall group	-P 1	-P 1
Moiety formula	O16 Si8	O2 Si
Sum formula	O16 Si8	O2 Si
Mr	480.72	60.09
Dx,g cm-3	4.462	4.462
Z	2	16
Mu (mm-1)	0.185	0.185
F000	480.0	480.0
F000'	480.04	
h,k,lmax	15,15,19	14,11,15
Nref	9264	2014
Tmin,Tmax		0.800,1.000
Tmin'		

Correction method= # Reported T Limits: Tmin=0.800 Tmax=1.000  
AbsCorr = MULTI-SCAN

Data completeness= 0.217                      Theta(max)= 19.569

R(reflections)= 0.0555( 1562)                      wR2(reflections)= 0.1399( 2014)

S = 1.167                      Npar= 137

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The following ALERTS were generated. Each ALERT has the format

**test-name\_ALERT\_alert-type\_alert-level.**

Click on the hyperlinks for more details of the test.

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**Alert level A**

PLAT029\_ALERT\_3\_A \_diffrn\_measured\_fraction\_theta\_full value Low . 0.370 Why?

**Author Response: The dataset was incomplete since the data were collected in a diamond anvil cell metallic body of which shadows more than 60% of the reflections.**

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**Alert level B**

PLAT911\_ALERT\_3\_B Missing FCF Refl Between Thmin & STh/L= 0.600 808 Report

**Author Response: Certain part of the reflections is missing due to geometry of the experiment. The metallic body of the diamond anvil cell absorbs more than 60% of the reflections.**

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**Alert level C**

PLAT230\_ALERT\_2\_C Hirshfeld Test Diff for Si1 --Si4\_k . 5.5 s.u.  
PLAT230\_ALERT\_2\_C Hirshfeld Test Diff for Si2 --Si8\_d . 5.4 s.u.  
PLAT230\_ALERT\_2\_C Hirshfeld Test Diff for Si4 --Si1\_k . 5.5 s.u.  
PLAT230\_ALERT\_2\_C Hirshfeld Test Diff for Si8 --Si2\_c . 5.4 s.u.  
PLAT250\_ALERT\_2\_C Large U3/U1 Ratio for Average U(i,j) Tensor .... 2.6 Note  
PLAT906\_ALERT\_3\_C Large K Value in the Analysis of Variance ..... 7.325 Check  
PLAT910\_ALERT\_3\_C Missing # of FCF Reflection(s) Below Theta(Min). 8 Note

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**Alert level G**

ABSMU01\_ALERT\_1\_G Calculation of \_exptl\_absorpt\_correction\_mu  
not performed for this radiation type.  
PLAT004\_ALERT\_5\_G Polymeric Structure Found with Maximum Dimension 3 Info  
PLAT012\_ALERT\_1\_G N.O.K. \_shelx\_res\_checksum Found in CIF ..... Please Check  
PLAT042\_ALERT\_1\_G Calc. and Reported MoietyFormula Strings Differ Please Check  
PLAT045\_ALERT\_1\_G Calculated and Reported Z Differ by a Factor ... 0.13 Check  
PLAT396\_ALERT\_2\_G Deviating Si-O-Si Angle From 150 for O4 127.4 Degree  
PLAT396\_ALERT\_2\_G Deviating Si-O-Si Angle From 150 for O10 120.7 Degree  
PLAT396\_ALERT\_2\_G Deviating Si-O-Si Angle From 150 for O11 131.1 Degree  
PLAT432\_ALERT\_2\_G Short Inter X...Y Contact Si1 ..015 3.20 Ang.  
PLAT432\_ALERT\_2\_G Short Inter X...Y Contact Si4 ..07 3.28 Ang.  
PLAT432\_ALERT\_2\_G Short Inter X...Y Contact Si4 ..Si6 3.47 Ang.  
PLAT432\_ALERT\_2\_G Short Inter X...Y Contact Si5 ..09 3.10 Ang.  
PLAT432\_ALERT\_2\_G Short Inter X...Y Contact Si5 ..010 3.25 Ang.  
PLAT432\_ALERT\_2\_G Short Inter X...Y Contact Si7 ..03 3.11 Ang.  
PLAT432\_ALERT\_2\_G Short Inter X...Y Contact Si7 ..Si8 3.13 Ang.  
PLAT432\_ALERT\_2\_G Short Inter X...Y Contact Si7 ..09 3.13 Ang.  
PLAT432\_ALERT\_2\_G Short Inter X...Y Contact Si7 ..06 3.21 Ang.  
PLAT432\_ALERT\_2\_G Short Inter X...Y Contact Si8 ..016 3.05 Ang.  
PLAT432\_ALERT\_2\_G Short Inter X...Y Contact Si8 ..015 3.34 Ang.  
PLAT912\_ALERT\_4\_G Missing # of FCF Reflections Above STh/L= 0.600 4858 Note  
PLAT913\_ALERT\_3\_G Missing # of Very Strong Reflections in FCF .... 2 Note  
PLAT933\_ALERT\_2\_G Number of OMIT Records in Embedded .res File ... 19 Note

PLAT951_ALERT_5_G	Calculated (ThMax) and CIF-Reported Kmax Differ	4 Units
PLAT952_ALERT_5_G	Calculated (ThMax) and CIF-Reported Lmax Differ	4 Units
PLAT957_ALERT_1_G	Calculated (ThMax) and Actual (FCF) Kmax Differ	4 Units
PLAT958_ALERT_1_G	Calculated (ThMax) and Actual (FCF) Lmax Differ	4 Units

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- 1 **ALERT level A** = Most likely a serious problem - resolve or explain
  - 1 **ALERT level B** = A potentially serious problem, consider carefully
  - 7 **ALERT level C** = Check. Ensure it is not caused by an omission or oversight
  - 26 **ALERT level G** = General information/check it is not something unexpected
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- 6 ALERT type 1 CIF construction/syntax error, inconsistent or missing data
  - 20 ALERT type 2 Indicator that the structure model may be wrong or deficient
  - 5 ALERT type 3 Indicator that the structure quality may be low
  - 1 ALERT type 4 Improvement, methodology, query or suggestion
  - 3 ALERT type 5 Informative message, check
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It is advisable to attempt to resolve as many as possible of the alerts in all categories. Often the minor alerts point to easily fixed oversights, errors and omissions in your CIF or refinement strategy, so attention to these fine details can be worthwhile. In order to resolve some of the more serious problems it may be necessary to carry out additional measurements or structure refinements. However, the purpose of your study may justify the reported deviations and the more serious of these should normally be commented upon in the discussion or experimental section of a paper or in the "special\_details" fields of the CIF. checkCIF was carefully designed to identify outliers and unusual parameters, but every test has its limitations and alerts that are not important in a particular case may appear. Conversely, the absence of alerts does not guarantee there are no aspects of the results needing attention. It is up to the individual to critically assess their own results and, if necessary, seek expert advice.

### **Publication of your CIF in IUCr journals**

A basic structural check has been run on your CIF. These basic checks will be run on all CIFs submitted for publication in IUCr journals (*Acta Crystallographica*, *Journal of Applied Crystallography*, *Journal of Synchrotron Radiation*); however, if you intend to submit to *Acta Crystallographica Section C* or *E* or *IUCrData*, you should make sure that full publication checks are run on the final version of your CIF prior to submission.

### **Publication of your CIF in other journals**

Please refer to the *Notes for Authors* of the relevant journal for any special instructions relating to CIF submission.

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**PLATON version of 30/01/2018; check.def file version of 30/01/2018**

